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Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	440
Number of Logic Elements/Cells	3520
Total RAM Bits	81920
Number of I/O	93
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	121-VFBGA
Supplier Device Package	121-UCBGA (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/ice40lp4k-cm121tr

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iCE40 LP/HX Family Data Sheet Introduction

March 2017 Data Sheet DS1040

Features

■ Flexible Logic Architecture

 Five devices with 384 to 7,680 LUT4s and 10 to 206 I/Os

■ Ultra Low Power Devices

- Advanced 40 nm low power process
- As low as 21 μA standby power
- Programmable low swing differential I/Os

■ Embedded and Distributed Memory

 Up to 128 kbits sysMEM[™] Embedded Block RAM

■ Pre-Engineered Source Synchronous I/O

• DDR registers in I/O cells

■ High Current LED Drivers

Three High Current Drivers used for three different LEDs or one RGB LED

■ High Performance, Flexible I/O Buffer

- Programmable sysIO[™] buffer supports wide range of interfaces:
 - LVCMOS 3.3/2.5/1.8
 - LVDS25E, subLVDS

- Schmitt trigger inputs, to 200 mV typical hysteresis
- Programmable pull-up mode

■ Flexible On-Chip Clocking

- Eight low-skew global clock resources
- Up to two analog PLLs per device

■ Flexible Device Configuration

- SRAM is configured through:
 - Standard SPI Interface
 - Internal Nonvolatile Configuration Memory (NVCM)

Broad Range of Package Options

- WLCSP, QFN, VQFP, TQFP, ucBGA, caBGA, and csBGA package options
- · Small footprint package options
 - As small as 1.40 mm x 1.48 mm
- · Advanced halogen-free packaging

Table 1-1. iCE40 Family Selection Guide

Part Number		LP384 LP640 LP1K LP4K LP8K HX1K HX4K				HX4K	HX8K		
Logic Cells (LUT + Flip-Flop)		384	640	1,280	3,520	7,680	1,280	3,520	7,680
RAM4K Memory Blocks		0	8	16	20	32	16	20	32
RAM4K RAM bits		0	32K	64K	80K	128K	64K	80K	128K
Phase-Locked Loops (PLLs)		0	0	1 ¹	2 ²	2 ²	1 ¹	2	2
Maximum Programmable I/C) Pins	63	25	95	167	178	95	95	206
Maximum Differential Input F	Pairs	8	3	12	20	23	11	12	26
High Current LED Drivers		0 3 3 0 0 0 0			0	0			
Package	Code			Programn	nable I/O: I	Max Inputs	(LVDS25)	•	
16 WLCSP (1.40 mm x 1.48 mm, 0.35 mm)	SWG16		10(0) ¹	10(0) ¹					
32 QFN (5 mm x 5 mm, 0.5 mm)	SG32	21(3)							
36 ucBGA (2.5 mm x 2.5 mm, 0.4 mm)	CM36	25(3)		25(3) ¹					
49 ucBGA (3 mm x 3 mm, 0.4 mm)	CM49	37(6)		35(5) ¹					
81 ucBGA (4 mm x 4 mm, 0.4 mm)	CM81			63(8)	63(9) ²	63(9) ²			
81 csBGA (5 mm x 5 mm, 0.5 mm)	CB81			62(9) ¹					

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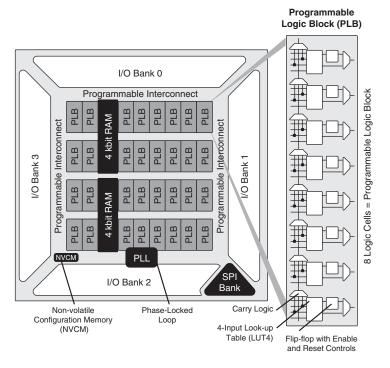
iCE40 LP/HX Family Data Sheet Architecture

March 2017 Data Sheet DS1040

Architecture Overview

The iCE40 family architecture contains an array of Programmable Logic Blocks (PLB), sysCLOCK™ PLLs, Non-volatile Programmable Configuration Memory (NVCM) and blocks of sysMEM™ Embedded Block RAM (EBR) surrounded by Programmable I/O (PIO). Figure 2-1 shows the block diagram of the iCE40LP/HX1K device.

Figure 2-1. iCE40LP/HX1K Device, Top View



The logic blocks, Programmable Logic Blocks (PLB) and sysMEM EBR blocks, are arranged in a two-dimensional grid with rows and columns. Each column has either logic blocks or EBR blocks. The PIO cells are located at the periphery of the device, arranged in banks. The PLB contains the building blocks for logic, arithmetic, and register functions. The PIOs utilize a flexible I/O buffer referred to as a sysIO buffer that supports operation with a variety of interface standards. The blocks are connected with many vertical and horizontal routing channel resources. The place and route software tool automatically allocates these routing resources.

In the iCE40 family, there are up to four independent sysIO banks. Note on some packages V_{CCIO} banks are tied together. There are different types of I/O buffers on the different banks. Refer to the details in later sections of this document. The sysMEM EBRs are large 4 kbit, dedicated fast memory blocks. These blocks can be configured as RAM, ROM or FIFO.

The iCE40 architecture also provides up to two sysCLOCK Phase Locked Loop (PLL) blocks. The PLLs have multiply, divide, and phase shifting capabilities that are used to manage the frequency and phase relationships of the clocks.

Every device in the family has a SPI port that supports programming and configuration of the device. The iCE40 includes on-chip, Nonvolatile Configuration Memory (NVCM).

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RAM Initialization and ROM Operation

If desired, the contents of the RAM can be pre-loaded during device configuration.

By preloading the RAM block during the chip configuration cycle and disabling the write controls, the sysMEM block can also be utilized as a ROM.

Note the sysMEM Embedded Block RAM Memory address 0 cannot be initialized.

Memory Cascading

Larger and deeper blocks of RAM can be created using multiple EBR sysMEM Blocks.

RAM4k Block

Figure 2-4 shows the 256x16 memory configurations and their input/output names. In all the sysMEM RAM modes, the input data and addresses for the ports are registered at the input of the memory array.

Figure 2-4. sysMEM Memory Primitives

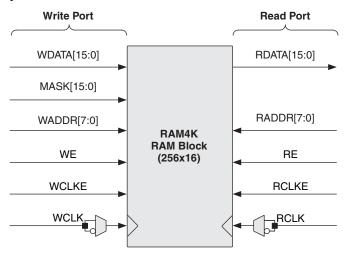


Table 2-5. EBR Signal Descriptions

Signal Name	Direction	Description
WDATA[15:0]	Input	Write Data input.
MASK[15:0]	Input	Masks write operations for individual data bit-lines. 0 = write bit; 1 = don't write bit
WADDR[7:0]	Input	Write Address input. Selects one of 256 possible RAM locations.
WE	Input	Write Enable input.
WCLKE	Input	Write Clock Enable input.
WCLK	Input	Write Clock input. Default rising-edge, but with falling-edge option.
RDATA[15:0]	Output	Read Data output.
RADDR[7:0]	Input	Read Address input. Selects one of 256 possible RAM locations.
RE	Input	Read Enable input.
RCLKE	Input	Read Clock Enable input.
RCLK	Input	Read Clock input. Default rising-edge, but with falling-edge option.

For further information on the sysMEM EBR block, please refer to TN1250, Memory Usage Guide for iCE40 Devices.



sys_IO

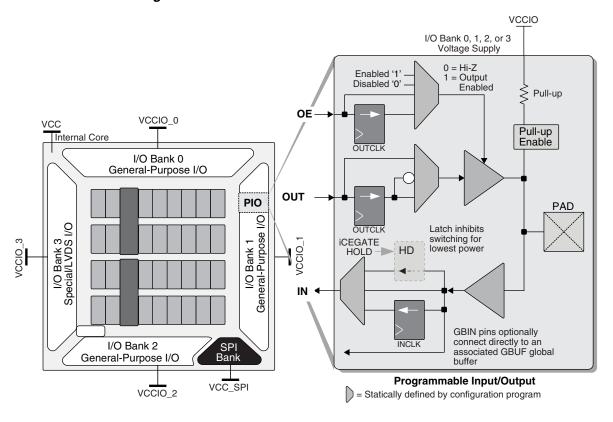
Buffer Banks

iCE40 devices have up to four I/O banks with independent V_{CCIO} rails with an additional configuration bank $V_{CC\ SPI}$ for the SPI I/Os.

Programmable I/O (PIO)

The programmable logic associated with an I/O is called a PIO. The individual PIO are connected to their respective sysIO buffers and pads. The PIOs are placed on all four sides of the device.

Figure 2-5. I/O Bank and Programmable I/O Cell



The PIO contains three blocks: an input register block, output register block iCEgate[™] and tri-state register block. To save power, the optional iCEgate[™] latch can selectively freeze the state of individual, non-registered inputs within an I/O bank. Note that the freeze signal is common to the bank. These blocks can operate in a variety of modes along with the necessary clock and selection logic.

Input Register Block

The input register blocks for the PIOs on all edges contain registers that can be used to condition high-speed interface signals before they are passed to the device core. In Generic DDR mode, two registers are used to sample the data on the positive and negative edges of the system clock signal, creating two data streams.

Output Register Block

The output register block can optionally register signals from the core of the device before they are passed to the sysIO buffers. In Generic DDR mode, two registers are used to capture the data on the positive and negative edge of the system clock and then muxed creating one data stream.

Figure 2-6 shows the input/output register block for the PIOs.



Figure 2-6. iCE I/O Register Block Diagram

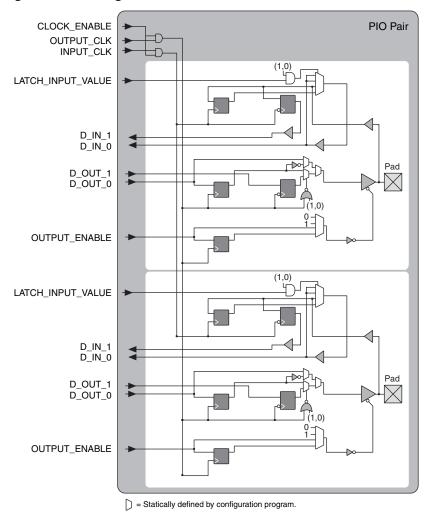


Table 2-6. PIO Signal List

Pin Name	I/O Type	Description
OUTPUT_CLK	Input	Output register clock
CLOCK_ENABLE	Input	Clock enable
INPUT_CLK	Input	Input register clock
OUTPUT_ENABLE	Input	Output enable
D_OUT_0/1	Input	Data from the core
D_IN_0/1	Output	Data to the core
LATCH_INPUT_VALUE	Input	Latches/holds the Input Value

sysIO Buffer

Each I/O is associated with a flexible buffer referred to as a sysIO buffer. These buffers are arranged around the periphery of the device in groups referred to as banks. The sysIO buffers allow users to implement a wide variety of standards that are found in today's systems including LVCMOS and LVDS25.

High Current LED Drivers combine three sysIO buffers together. This allows for programmable drive strength. This also allows for high current drivers that are ideal to drive three white LEDs, or one RGB LED. Each bank is capable of supporting multiple I/O standards including single-ended LVCMOS buffers and differential LVDS25E output buf-



Power On Reset

iCE40 devices have power-on reset circuitry to monitor V_{CC} , V_{CCIO_2} , V_{PP_2V5} , and V_{CC_SPI} voltage levels during power-up and operation. At power-up, the POR circuitry monitors V_{CC} , V_{CCIO_2} , V_{PP_2V5} , and V_{CC_SPI} (controls configuration) voltage levels. It then triggers download from the on-chip NVCM or external Flash memory after reaching the power-up levels specified in the Power-On-Reset Voltage table in the DC and Switching Characteristics section of this data sheet. Before and during configuration, the I/Os are held in tri-state. I/Os are released to user functionality once the device has finished configuration.

Programming and Configuration

This section describes the programming and configuration of the iCE40 family.

Device Programming

The NVCM memory can be programmed through the SPI port.

Device Configuration

There are various ways to configure the Configuration RAM (CRAM) including:

- 1. Internal NVCM Download
- 2. From a SPI Flash (Master SPI mode)
- 3. System microprocessor to drive a Serial Slave SPI port (SSPI mode)

The image to configure the CRAM can be selected by the user on power up (Cold Boot) or once powered up (Warm Boot).

For more details on programming and configuration, see TN1248, iCE40 Programming and Configuration Usage Guide.

Power Saving Options

iCE40 devices are available in two options for maximum flexibility: LP and HX devices. The LP devices have ultra low static and dynamic power consumption. HX devices are designed to provide high performance. Both the LP and the HX devices operate at 1.2 V $V_{\rm CC}$.

iCE40 devices feature iCEGate and PLL low power mode to allow users to meet the static and dynamic power requirements of their applications. While these features are available in both device types, these features are mainly intended for use with iCE40 LP devices to manage power consumption.

Table 2-9. iCE40 Power Saving Features Description

Device Subsystem	Feature Description
	When LATCHINPUTVALUE is enabled, forces the PLL into low-power mode; PLL output held static at last input clock value.
	To save power, the optional iCEgate latch can selectively freeze the state of individual, non-registered inputs within an I/O bank. Registered inputs are effectively frozen by their associated clock or clock-enable control.



Static Supply Current – HX Devices^{1, 2, 3, 4}

Symbol	Symbol Parameter		Typ. V _{CC} ⁴	Units
Icc		iCE40HX1K	296	μΑ
		iCE40HX4K	1140	μΑ
		iCE40HX8K	1140	μΑ
I _{CCPLL} ⁵	PLL Power Supply	All devices	0.5	μΑ
I _{PP_2V5}	NVCM Power Supply	All devices	1.0	μΑ
Iccio, Icc_spi	Bank Power Supply ⁴ V _{CCIO} = 2.5 V	All devices	3.5	μΑ

Assumes blank pattern with the following characteristics: all outputs are tri-stated, all inputs are configured as LVCMOS and held at V_{CCIO} or GND, on-chip PLL is off. For more detail with your specific design, use the Power Calculator tool. Power specified with master SPI configuration mode. Other modes may be up to 25% higher.

- 2. Frequency = 0 MHz.
- 3. $T_J = 25$ °C, power supplies at nominal voltage.
- 4. Does not include pull-up.
- 5. $V_{\mbox{\footnotesize CCPLL}}$ is tied to $V_{\mbox{\footnotesize CC}}$ internally in packages without PLLs pins.

Programming NVCM Supply Current – LP Devices^{1, 2, 3, 4}

Symbol	Parameter	Device	Typ. V _{CC} ⁵	Units
		iCE40LP384	60	μΑ
		iCE40LP640	120	μΑ
I _{CC}	Core Power Supply	iCE40LP1K	120	μΑ
		iCE40LP4K	350	μΑ
		iCE40LP8K	350	μΑ
I _{CCPLL} ^{6, 7}	PLL Power Supply	All devices	0.5	μΑ
I _{PP_2V5}	NVCM Power Supply	All devices	2.5	mA
I _{CCIO⁸, I_{CC_SPI}}	Bank Power Supply⁵	All devices	3.5	mA

- 1. Assumes all inputs are held at $V_{\mbox{\scriptsize CCIO}}$ or GND and all outputs are tri-stated.
- 2. Typical user pattern.
- 3. SPI programming is at 8 MHz.
- 4. $T_{.1} = 25$ °C, power supplies at nominal voltage.
- 5. Per bank. $V_{CCIO} = 2.5 \text{ V}$. Does not include pull-up.
- 6. No PLL available on the iCE40-LP384 and iCE40-LP640 device.
- 7. $V_{\mbox{\footnotesize CCPLL}}$ is tied to $V_{\mbox{\footnotesize CC}}$ internally in packages without PLLs pins.
- 8. V_{PP_FAST}, used only for fast production programming, must be left floating or unconnected in applications, except CM36 and CM49 packages MUST have the V_{PP_FAST} ball connected to V_{CCIO_0} ball externally.



Peak Startup Supply Current – HX Devices

Symbol	Parameter	Device	Max	Units
		iCE40HX1K	6.9	mA
I _{CCPEAK}	Core Power Supply	iCE40HX4K	22.3	mA
		iCE40HX8K	22.3	mA
		iCE40HX1K	1.8	mA
I _{CCPLLPEAK} ¹	PLL Power Supply	iCE40HX4K	6.4	mA
		iCE40HX8K	6.4	mA
		iCE40HX1K	2.8	mA
I _{PP_2V5PEAK}	NVCM Power Supply	iCE40HX4K	4.1	mA
		iCE40HX8K	4.1	mA
ICCIOPEAK, ICC_SPIPEAK		iCE40HX1K	6.8	mA
	Bank Power Supply	iCE40HX4K	6.8	mA
		iCE40HX8K	6.8	mA

^{1.} $\rm V_{CCPLL}$ is tied to $\rm V_{CC}$ internally in packages without PLLs pins.

sysIO Recommended Operating Conditions

	V _{CCIO} (V)				
Standard	Min.	Тур.	Max.		
LVCMOS 3.3	3.14	3.3	3.46		
LVCMOS 2.5	2.37	2.5	2.62		
LVCMOS 1.8	1.71	1.8	1.89		
LVDS25E ^{1, 2}	2.37	2.5	2.62		
subLVDSE ^{1, 2}	1.71	1.8	1.89		

^{1.} Inputs on-chip. Outputs are implemented with the addition of external resistors.

sysIO Single-Ended DC Electrical Characteristics

Input/	V _{IL}		V _{IH} ¹			\/ B#1		
Output Standard	Min. (V)	Max. (V)	Min. (V)	Max. (V)	V _{OL} Max. (V)	V _{OH} Min. (V)	I _{OL} Max. (mA)	I _{OH} Max. (mA)
LVCMOS 3.3	-0.3	0.8	2.0	V _{CCIO} + 0.2 V	0.4	V _{CCIO} - 0.4	8, 16 ² , 24 ²	$-8, -16^2, -24^2$
LV OIVIOU 3.5	0.0	0.0	2.0	2.0 V _{CCIO} + 0.2 V	0.2	V _{CCIO} - 0.2	0.1	-0.1
LVCMOS 2.5	-0.3	0.7	1.7	V + 0.2 V	0.4	V _{CCIO} - 0.4	6, 12 ² , 18 ²	$-6, -12^2, -18^2$
LV CIVIOS 2.5	-0.5	0.7	1.7 $V_{CCIO} + 0.2 V$	VCCIO + 0.2 V	0.2	V _{CCIO} - 0.2	0.1	-0.1
LVCMOS 1.8	-0.3	0.35V _{CCIO}	0.65V _{CCIO}	V 0.2.V	0.4	V _{CCIO} - 0.4	4, 8 ² , 12 ²	-4, -8 ² , -12 ²
LVCIVIOS 1.8	-0.5	0.33 V CCIO	0.03 V CCIO	V _{CCIO} + 0.2 V	0.2	V _{CCIO} - 0.2	0.1	-0.1

^{1.} Some products are clamped to a diode when V_{IN} is larger than $V_{\text{CCIO.}}$

^{2.} Does not apply to Configuration Bank V_{CC SPI}.

^{2.} Only for High Drive LED outputs.



LVDS25E Emulation

iCE40 devices can support LVDSE outputs via emulation on all banks. The output is emulated using complementary LVCMOS outputs in conjunction with resistors across the driver outputs on all devices. The scheme shown in Figure 3-1 is one possible solution for LVDS25E standard implementation. Resistor values in Figure 3-1 are industry standard values for 1% resistors.

Figure 3-1. LVDS25E Using External Resistors

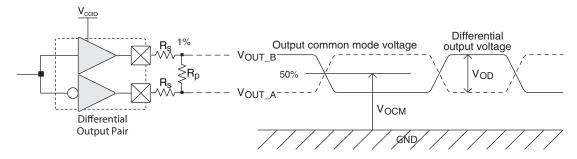


Table 3-1. LVDS25E DC Conditions

Parameter	Description	Тур.	Units
Z _{OUT}	Output impedance	20	Ohms
R _S	Driver series resistor	150	Ohms
R _P	Driver parallel resistor	140	Ohms
R _T	Receiver termination	100	Ohms
V _{OH}	Output high voltage	1.43	V
V _{OL}	Output low voltage	1.07	V
V _{OD}	Output differential voltage	0.30	V
V _{CM}	Output common mode voltage	1.25	V
Z _{BACK}	Back impedance	100.5	Ohms
I _{DC}	DC output current	6.03	mA



Typical Building Block Function Performance – LP Devices^{1, 2}

Pin-to-Pin Performance (LVCMOS25)

Function	Timing	Units
Basic Functions		•
16-bit decoder	11.0	ns
4:1 MUX	12.0	ns
16:1 MUX	13.0	ns

Register-to-Register Performance

Function	Timing	Units	
Basic Functions	<u> </u>	•	
16:1 MUX	190	MHz	
16-bit adder	160	MHz	
16-bit counter	175	MHz	
64-bit counter	65	MHz	
Embedded Memory Functions	·	•	
256x16 Pseudo-Dual Port RAM	240	MHz	

The above timing numbers are generated using the iCECube2 design tool. Exact performance may vary with device and tool version. The tool uses internal parameters that have been characterized but are not tested on every device.

Typical Building Block Function Performance – HX Devices^{1, 2} Pin-to-Pin Performance (LVCMOS25)

Function	Timing	Units
Basic Functions		
16-bit decoder	10.0	ns
4:1 MUX	9.0	ns
16:1 MUX	9.5	ns

Register-to-Register Performance

Function	Timing	Units
Basic Functions	•	·
16:1 MUX	305	MHz
16-bit adder	220	MHz
16-bit counter	255	MHz
64-bit counter	105	MHz
Embedded Memory Functions	•	·
256x16 Pseudo-Dual Port RAM	403	MHz

^{1.} The above timing numbers are generated using the iCECube2 design tool. Exact performance may vary with device and tool version. The tool uses internal parameters that have been characterized but are not tested on every device.

^{2.} Using a V_{CC} of 1.14 V at Junction Temp 85 °C.

^{2.} Using a V_{CC} of 1.14 V at Junction Temp 85 °C.



Derating Logic Timing

Logic timing provided in the following sections of the data sheet and the Lattice design tools are worst case numbers in the operating range. Actual delays may be much faster. Lattice design tools can provide logic timing numbers at a particular temperature and voltage.

Maximum sysIO Buffer Performance²

I/O Standard	Max. Speed	Units				
	Inputs					
LVDS25 ¹	400	MHz				
subLVDS18 ¹	400	MHz				
LVCMOS33	250	MHz				
LVCMOS25	250	MHz				
LVCMOS18	250	MHz				
Outputs						
LVDS25E	250	MHz				
subLVDS18E	155	MHz				
LVCMOS33	250	MHz				
LVCMOS25	250	MHz				
LVCMOS18	155	MHz				

^{1.} Supported in Bank 3 only.

iCE40 Family Timing Adders

Over Recommended Commercial Operating Conditions - LP Devices^{1, 2, 3, 4, 5}

Buffer Type	Description	Timing	Units
Input Adjusters			
LVDS25	LVDS, V _{CCIO} = 2.5 V	-0.18	ns
subLVDS	subLVDS, V _{CCIO} = 1.8 V	0.82	ns
LVCMOS33	LVCMOS, V _{CCIO} = 3.3 V	0.18	ns
LVCMOS25	LVCMOS, V _{CCIO} = 2.5 V	0.00	ns
LVCMOS18	LVCMOS, V _{CCIO} = 1.8 V	0.19	ns
Output Adjusters	·		
LVDS25E	LVDS, Emulated, V _{CCIO} = 2.5 V	0.00	ns
subLVDSE	subLVDS, Emulated, V _{CCIO} = 1.8 V	1.32	ns
LVCMOS33	LVCMOS, V _{CCIO} = 3.3 V	-0.12	ns
LVCMOS25	LVCMOS, V _{CCIO} = 2.5 V	0.00	ns
LVCMOS18	LVCMOS, V _{CCIO} = 1.8 V	1.32	ns

- 1. Timing adders are relative to LVCMOS25 and characterized but not tested on every device.
- 2. LVCMOS timing measured with the load specified in Switching Test Condition table.
- 3. All other standards tested according to the appropriate specifications.
- 4. Commercial timing numbers are shown.
- 5. Not all I/O standards are supported for all banks. See the Architecture section of this data sheet for details.

^{2.} Measured with a toggling pattern



iCE40 External Switching Characteristics – LP Devices 1,2

Parameter	Description	Device	Min.	Max.	Units
Clocks	·		•		•
Global Clocks					
f _{MAX_GBUF}	Frequency for Global Buffer Clock network	All iCE40LP devices	_	275	MHz
t _{W_GBUF}	Clock Pulse Width for Global Buffer	All iCE40LP devices	0.92	_	ns
		iCE40LP384	_	370	ps
		iCE40LP640	_	230	ps
t _{SKEW_GBUF}	Global Buffer Clock Skew Within a Device	iCE40LP1K	_	230	ps
		iCE40LP4K	_	340	ps
		iCE40LP8K	_	340	ps
Pin-LUT-Pin Propa	ngation Delay		•		•
t _{PD}	Best case propagation delay through one LUT-4	All iCE40LP devices	_	9.36	ns
General I/O Pin Pa	rameters (Using Global Buffer Clock withou	it PLL) ³	"		
		iCE40LP384		300	ps
		iCE40LP640	_	200	ps
t _{SKEW_IO}	Data bus skew across a bank of IOs	iCE40LP1K	_	200	ps
		iCE40LP4K	_	280	ps
		iCE40LP8K	_	280	ps
		iCE40LP384	_	6.33	ns
		iCE40LP640	_	5.91	ns
t _{CO} C	Clock to Output - PIO Output Register	iCE40LP1K	_	5.91	ns
		iCE40LP4K	_	6.58	ns
		iCE40LP8K	_	6.58	ns
		iCE40LP384	-0.08	_	ns
		iCE40LP640	-0.33	_	ns
t _{SU}	Clock to Data Setup - PIO Input Register	iCE40LP1K	-0.33		ns
		iCE40LP4K	-0.63	_	ns
su (iCE40LP8K	-0.63	_	ns
		iCE40LP384	1.99	_	ns
		iCE40LP640	2.81	_	ns
t _H	Clock to Data Hold - PIO Input Register	iCE40LP1K	2.81	_	ns
		iCE40LP4K	3.48	_	ns
		iCE40LP8K	3.48		ns
General I/O Pin Pa	rameters (Using Global Buffer Clock with P	•			
		iCE40LP1K		2.20	ns
t _{COPLL}	Clock to Output - PIO Output Register	iCE40LP4K		2.30	ns
		iCE40LP8K		2.30	ns
		iCE40LP1K	5.23	_	ns
t _{SUPLL}	Clock to Data Setup - PIO Input Register	iCE40LP4K	6.13	_	ns
		iCE40LP8K	6.13	_	ns



iCE40 External Switching Characteristics – LP Devices (Continued)^{1, 2}

Parameter	Description	Device	Min.	Max.	Units
		iCE40LP1K	-0.90	_	ns
t _{HPLL}	Clock to Data Hold - PIO Input Register	iCE40LP4K	-0.80	_	ns
		iCE40LP8K	-0.80	_	ns

^{1.} Exact performance may vary with device and design implementation. Commercial timing numbers are shown at 85 °C and 1.14 V. Other operating conditions can be extracted from the iCECube2 software.

^{2.} General I/O timing numbers based on LVCMOS 2.5, 0pf load.

^{3.} Supported on devices with a PLL.



iCE40 External Switching Characteristics – HX Devices 1,2

Parameter	Description	Device	Min.	Max.	Units
Clocks	-		l	l .	
Primary Clocks					
f _{MAX_GBUF}	Frequency for Global Buffer Clock network	All iCE40HX devices	_	275	MHz
t _{W_GBUF}	Clock Pulse Width for Global Buffer	All iCE40HX devices	0.88	_	ns
		iCE40HX1K	_	727	ps
t _{SKEW_GBUF}	Global Buffer Clock Skew Within a Device	iCE40HX4K	_	300	ps
		iCE40HX8K	_	300	ps
Pin-LUT-Pin Prop	pagation Delay		•		•
t _{PD}	Best case propagation delay through one LUT-4	All iCE40 HX devices	_	7.30	ns
General I/O Pin I	Parameters (Using Global Buffer Clock witho	ut PLL)	1	•	•
		iCE40HX1K	_	696	ps
t _{SKEW_IO}	Data bus skew across a bank of IOs	iCE40HX4K	_	290	ps
_		iCE40HX8K	_	290	ps
		iCE40HX1K	_	5.00	ns
t _{CO} Clock to 0	Clock to Output - PIO Output Register	iCE40HX4K	_	5.41	ns
		iCE40HX8K	_	5.41	ns
		iCE40HX1K	-0.23	_	ns
t _{SU}	Clock to Data Setup - PIO Input Register	iCE40HX4K	-0.43	_	ns
	Clock to Data Setup - PIO Input Register	iCE40HX8K	-0.43	_	ns
		iCE40HX1K	1.92	_	ns
t _H	Clock to Data Hold - PIO Input Register	iCE40HX4K	2.38	_	ns
		iCE40HX8K	2.38	_	ns
General I/O Pin I	Parameters (Using Global Buffer Clock with F	PLL) ³	•		•
		iCE40HX1K	_	2.96	ns
t _{COPLL}	Clock to Output - PIO Output Register	iCE40HX4K	_	2.51	ns
COPLL Clock to Guiput - 1 To Guiput Hegister		iCE40HX8K	_	2.51	ns
		iCE40HX1K	3.10	_	ns
t _{SUPLL}	Clock to Data Setup - PIO Input Register	iCE40HX4K	4.16	_	ns
		iCE40HX8K	4.16	_	ns
		iCE40HX1K	-0.60	_	ns
t _{HPLL}	Clock to Data Hold - PIO Input Register	iCE40HX4K	-0.53	_	ns
		iCE40HX8K	-0.53	_	ns

^{1.} Exact performance may vary with device and design implementation. Commercial timing numbers are shown at 85 °C and 1.14 V. Other operating conditions, including industrial, can be extracted from the iCECube2 software.

^{2.} General I/O timing numbers based on LVCMOS 2.5, 0pf load.

^{3.} Supported on devices with a PLL.



sysCONFIG Port Timing Specifications¹

Symbol	Parameter		Min.	Тур.	Max.	Units
All Configuration	on Modes				l .	·I
^t CRESET_B	Minimum CRESET_B Low pulse width required to restart configuration, from falling edge to rising edge		200	_	_	ns
t _{DONE_IO}	Number of configuration clock cycles after CDONE goes High before the PIO pins are activated		49	_	_	Clock Cycles
Slave SPI	•				•	•
	Minimum time from a rising edge	iCE40LP384	600	-	_	us
t _{CR_SCK}	on CRESET_B until the first SPI write operation, first SPI_SCK. During this time, the iCE40	iCE40LP640, iCE40LP/HX1K	800	-	_	us
	device is clearing its internal con-	iCE40LP/HX4K	1200	-	_	us
	figuration memory	iCE40LP/HX8K	1200	-	_	us
		Write	1	-	25	MHz
f _{MAX} ¹		Read iCE40LP384 ²	-	15	-	MHz
	CCLK clock frequency	Read iCE40LP640, iCE40LP/HX1K ²	-	15	-	MHz
		Read iCE40LP/ HX4K ²	-	15	-	MHz
		Read iCE40LP/ HX8K ²	-	15	-	MHz
t _{CCLKH}	CCLK clock pulse width high		20	_	_	ns
t _{CCLKL}	CCLK clock pulse width low		20	_	_	ns
t _{STSU}	CCLK setup time		12		_	ns
t _{STH}	CCLK hold time		12		_	ns
t _{STCO}	CCLK falling edge to valid output		13		_	ns
Master SPI	·					
		Off	_	0	_	MHz
f _{MCLK}	MCLK clock frequency	Low Frequency (Default)	_	7.5	_	MHz
		Medium Frequency ³	_	24		MHz
		High Frequency ³	_	40	_	MHz



iCE40 LP/HX Family Data Sheet Pinout Information

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Signal Descriptions

Signal Name	I/O	Descriptions
General Purpose	·	
IO[Bank]_[Row/Column Number][A/B]	I/O	[Bank] indicates the bank of the device on which the pad is located. [Number] indicates IO number on the device.
IO[Bank]_[Row/Column Number][A/B]	I/O	[Bank] indicates the bank of the device on which the pad is located. [Number] indicates IO number on the device. [A/B] indicates the differential I/O. 'A' = negative input. 'B' = positive input.
HCIO[Bank]_[Number]	I/O	High Current IO. [Bank] indicates the bank of the device on which the pad is located. [Number] indicates IO number.
NC	_	No connect
GND	_	GND – Ground. Dedicated pins. It is recommended that all GNDs are tied together.
VCC	_	VCC – The power supply pins for core logic. Dedicated pins. It is recommended that all VCCs are tied to the same supply.
VCCIO_x	_	VCCIO – The power supply pins for I/O Bank x. Dedicated pins. All VCCIOs located in the same bank are tied to the same supply.
PLL and Global Functions	(Used as ι	ser-programmable I/O pins when not used for PLL or clock pins)
VCCPLLx	_	PLL VCC – Power. Dedicated pins. The PLL requires a separate power and ground that is quiet and stable to reduce the output clock jitter of the PLL.
GNDPLLx	_	PLL GND – Ground. Dedicated pins. The sysCLOCK PLL has the DC ground connection made on the FPGA, so the external PLL ground connection (GNDPLL) must NOT be connected to the board's ground.
GBINx	_	Global pads. Two per side.
Programming and Configu	ration	
CBSEL[0:1]	I/O	Dual function pins. I/Os when not used as CBSEL. Optional ColdBoot configuration SELect input, if ColdBoot mode is enabled.
CRESET_B	I	Configuration Reset, active Low. Dedicated input. No internal pull-up resistor. Either actively drive externally or connect a 10 KOhm pull-up resistor to VCCIO_2.
CDONE	I/O	Configuration Done. Includes a permanent weak pull-up resistor to VCCIO_2. If driving external devices with CDONE output, an external pull-up resistor to VCCIO_2 may be required. Refer to the TN1248, iCE40 Programming and Configuration for more details. Following device configuration the iCE40LP640 and iCE40LP1K in the SWG16 package CDONE pin can be used as a user output.
VCC_SPI	_	SPI interface voltage supply input. Must have a valid voltage even if configuring from NVCM.
SPI_SCK	I/O	Input Configuration Clock for configuring an FPGA in Slave SPI mode. Output Configuration Clock for configuring an FPGA configuration modes.
SPI_SS_B	I/O	SPI Slave Select. Active Low. Includes an internal weak pull-up resistor to VCC_SPI during configuration. During configuration, the logic level sampled on this pin determines the configuration mode used by the iCE40 device. An input when sampled at the start of configuration. An input when in SPI Peripheral configuration mode (SPI_SS_B = Low). An output when in Master SPI Flash configuration mode.
SPI_SI	I/O	Slave SPI serial data input and master SPI serial data output
SPI_SO	I/O	Slave SPI serial data output and master SPI serial data input



Signal Descriptions (Continued)

Signal Name	I/O	Descriptions
VPP_FAST	_	Optional fast NVCM programming supply. V_{PP_FAST} , used only for fast production programming, must be left floating or unconnected in applications, except CM36 and CM49 packages MUST have the V_{PP_FAST} ball connected to V_{CCIO_0} ball externally.
VPP_2V5	_	VPP_2V5 NVCM programming and operating supply



Pin Information Summary (Continued)

General Purpose I/O per B Bank 0 Bank 1 Bank 2 Bank 3 Configuration Total General Purpose Single Ended I/O High Current Outputs per Bank 0	17 15 9 18 4 63 Bank	23 21 19 26 4 93	46 42 40 46 4 178	17 15 9 18 4	23 21 19	46 42	VQ100 19 19	24 25	TQ144
Bank 0 Bank 1 Bank 2 Bank 3 Configuration Total General Purpose Single Ended I/O High Current Outputs per	17 15 9 18 4 63 Bank	21 19 26 4	42 40 46 4	15 9 18	21 19	42			
Bank 1 Bank 2 Bank 3 Configuration Total General Purpose Single Ended I/O High Current Outputs per	15 9 18 4 63 Bank	21 19 26 4	42 40 46 4	15 9 18	21 19	42			
Bank 2 Bank 3 Configuration Total General Purpose Single Ended I/O High Current Outputs per	9 18 4 63 Bank	19 26 4	40 46 4	9 18	19		19	25	OF.
Bank 3 Configuration Total General Purpose Single Ended I/O High Current Outputs per	18 4 63 Bank 0	26 4	46	18		40			25
Configuration Total General Purpose Single Ended I/O High Current Outputs per	4 63 Bank 0	4	4		1	40	12	20	20
Total General Purpose Single Ended I/O High Current Outputs per	63 Bank			4	26	46	18	22	24
High Current Outputs per	Bank 0	93	178		4	4	4	4	4
	0			63	93	178	72	95	96
Bank 0					•	•	•		
		0	0	0	0	0	0	0	0
Bank 1	0	0	0	0	0	0	0	0	0
Bank 2	0	0	0	0	0	0	0	0	0
Bank 3	0	0	0	0	0	0	0	0	0
Total Differential Inputs	0	0	0	0	0	0	0	0	0
Differential Inputs per Bar	nk				•		•	•	
Bank 0	0	0	0	0	0	0	0	0	0
Bank 1	0	0	0	0	0	0	0	0	0
Bank 2	0	0	0	0	0	0	0	0	0
Bank 3	9	13	23	9	13	23	9	11	12
Total Differential Inputs	9	13	23	9	13	23	9	11	12
Dedicated Inputs per Bank	k					•	•	•	
Bank 0	0	0	0	0	0	0	0	0	0
Bank 1	0	0	1	0	0	1	0	1	1
Bank 2	2	2	2	2	2	2	2	2	2
Bank 3	0	0	0	0	0	0	0	0	0
Configuration	0	0	0	0	0	0	0	0	0
Total Dedicated Inputs	2	2	3	2	2	3	2	3	3
Vccio Pins					•				
Bank 0	1	1	3	1	1	3	2	2	2
Bank 1	1	1	3	1	1	3	2	2	2
Bank 2	1	1	3	1	1	3	2	2	2
Bank 3	1	2	4	1	2	4	3	3	2
VCC	3	4	8	3	4	8	4	5	4
VCC_SPI	1	1	1	1	1	1	1	1	1
VPP_2V5	1	1	1	1	1	1	1	1	1
VPP_FAST ¹	1	1	1	1	1	1	1	1	1
VCCPLL	1	2	2	1	2	2	0	1	1
GND	5	12	18	5	12	18	10	14	10
NC	0	0	0	0	0	0	0	2	19
Total Count of Bonded Pins	81	121	225	81	121	225	100	132	144

^{1.} V_{PP_FAST}, used only for fast production programming, must be left floating or unconnected in applications.



iCE40 LP/HX Family Data Sheet Revision History

March 2017 Data Sheet DS1040

Date	Version	Section	Change Summary		
March 2017	3.3	Introduction	Updated Features section. Added 121-ball caBGA package for ICE40 HX4K/8K to Table 1-1, iCE40 Family Selection Guide.		
		Architecture	Updated PLB Blocks section. Changed "subtracters" to "subtractors" in the Carry Logic description.		
			Updated Clock/Control Distribution Network section. Switched the "Clock Enable" and the "Reset" headings in Table 2-2, Global Buffer (GBUF) Connections to Programmable Logic Blocks.		
		Pinout Information	Updated Pin Information Summary section. Added BG121information under iCE40HX4K and iCE40HX8K.		
		Ordering Information	Updated iCE40 Part Number Description section. Added Shipping Method and BG121 package under High Performance (HX) Devices.		
			Updated Ordering Information section. Added part numbers for BG121 under High-Performance Industrial Grade Devices, Halogen Free (RoHS) Packaging.		
		Supplemental Information	Corrected reference to "Package Diagrams Data Sheet".		
October 2015	3.2	Introduction	Updated Features section. Added footnote to 16 WLCSP Programmable I/O: Max Inputs (LVDS25) in Table 1-1, iCE40 Family Selection Guide.		
		DC and Switching Characteristics	Updated sysCLOCK PLL Timing section. Changed t _{DT} conditions.		
			Updated Programming NVCM Supply Current – LP Devices section. Changed I _{PP_2V5} and I _{CCIO} , I _{CC_SPI} units.		
March 2015	3.1	DC and Switching Characteristics	Updated sysIO Single-Ended DC Electrical Characteristics section. Changed LVCMOS 3.3 and LVCMOS 2. 5 V _{OH} Min. (V) from 0.5 to 0.4.		
July 2014	3.0	DC and Switching Characteristics	Revised and/or added Typ. V _{CC} data in the following sections. — Static Supply Current – LP Devices — Static Supply Current – HX Devices — Programming NVCM Supply Current – LP Devices — Programming NVCM Supply Current – HX Devices In each section table, the footnote indicating Advanced device status was removed.		
		Pinout Information	Updated Pin Information Summary section. Added footnote 1 to CM49 under iCE40LP1K.		
April 2014	02.9	Ordering Information	Changed "i" to "I" in part number description and ordering part numbers.		
			Added part numbers to the Ultra Low Power Industrial Grade Devices, Halogen Free (RoHS) Packaging table.		